

ABSTRACT

An executive test system for testing an electronic device having selectable specifications. A user may select from multiple sets of specifications. The selected specification is then applied to test results and a display of the results of the application of the specification is shown.

Parameter	Unit	Value	Standard Error	t-Statistic	p-Value
Intercept		1.0000	0.0000	1.0000	0.0000
Age	Years	0.0000	0.0000	0.0000	0.0000
Gender		0.0000	0.0000	0.0000	0.0000
Marital Status		0.0000	0.0000	0.0000	0.0000
Education	Years	0.0000	0.0000	0.0000	0.0000
Income	Thousands of Dollars	0.0000	0.0000	0.0000	0.0000
Health		0.0000	0.0000	0.0000	0.0000
Smoking		0.0000	0.0000	0.0000	0.0000
Alcohol		0.0000	0.0000	0.0000	0.0000
Exercise		0.0000	0.0000	0.0000	0.0000
Stress		0.0000	0.0000	0.0000	0.0000
Family Size		0.0000	0.0000	0.0000	0.0000
Work Hours	Hours per Week	0.0000	0.0000	0.0000	0.0000
Job Satisfaction		0.0000	0.0000	0.0000	0.0000
Life Satisfaction		0.0000	0.0000	0.0000	0.0000
Residual Sum of Squares		0.0000	0.0000	0.0000	0.0000
Adjusted R-Square		0.0000	0.0000	0.0000	0.0000
F-Statistic		0.0000	0.0000	0.0000	0.0000
Prob(F-Statistic)		0.0000	0.0000	0.0000	0.0000